Sea	210	h A	In	tae
36	41 G	<i>II I</i> N	w	res



Application/Control No.	Applicant(s)/Patent Reexamination	under
10/697,241	FLUCK ET AL.	
Examiner	Art Unit	
Quang N. Nguyen	2141	

SEARCHED			
Class	Subclass	Date	Examiner
709	203	8/6/2007	QN
709	217	8/6/2007	QN ·
709	219	. 8/6/2007	QN
700	83	8/6/2007	QN
717	716	8/6/2007	QN
			٠.
		1	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	0		

SEARCH I (INCLUDING SEAR		<b>(</b> )
	DATE	EXMR
Inventor Name Search	8/6/2007	QN
East Search (see notes)	8/6/2007	QN